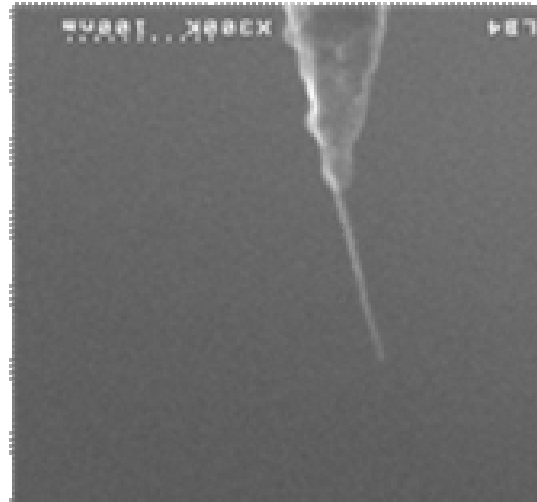
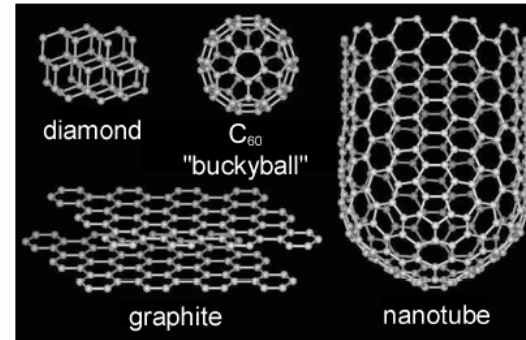
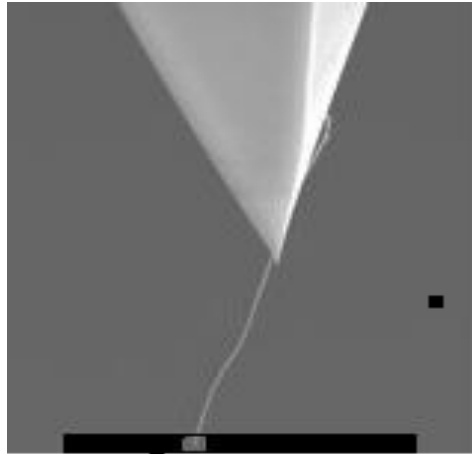


**Julien Buchoux, Sophie Marsaudon,  
Rodolphe Boisgard, Jean-Pierre Aimé,  
*CNRS-Université Bordeaux I.***

## **Carbon nanotube a Versatile AFM Tip**





- **CNT: Why? for doing What?**
- **CNT as AFM-tip: a simple mechanical nanosystem ?**
- **How does a CNT touch a surface?**

# Carbon nanotube as AFM Tip

Why CNT ?

- Well defined geometry at the nanoscale .
- Good Mechanical properties: no wear, Robust
- Chemically inert, very stable against molecular pollution
- Soft

What for?

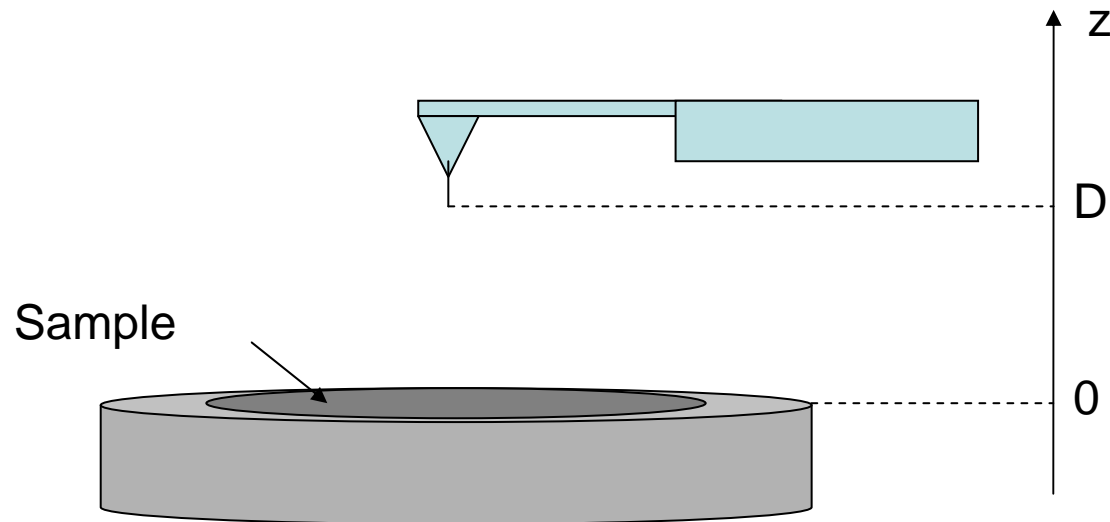
- Metrology: More accurate AFM Image, almost no tip dilation.
- Stable Tip sample interaction even on complex systems: relevant images are expected
- soft tip allowing to image proteins at work without damage?!

**Carbon nanotube as AFM tip: Work on began more than 10 years ago, still not widely used, nor is a large scale product  
WHY?**

# CNT AFM tip: a simple mechanical system?

Frequency Modulation mode and thermal noise studies:

Carbon Nanotube Stiffness  $k_{NT}$



➤ Frequency shift  $\Delta\nu = \nu - \nu_0$

➤ Dissipation

$$\frac{\Delta\nu}{\nu_0} \approx \frac{k_{NT}}{k_{cantilever}}$$

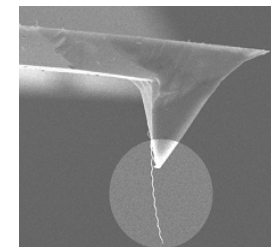
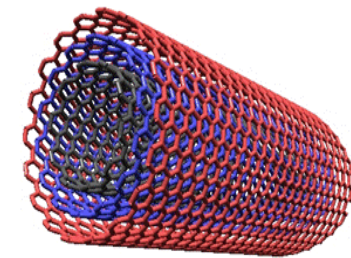
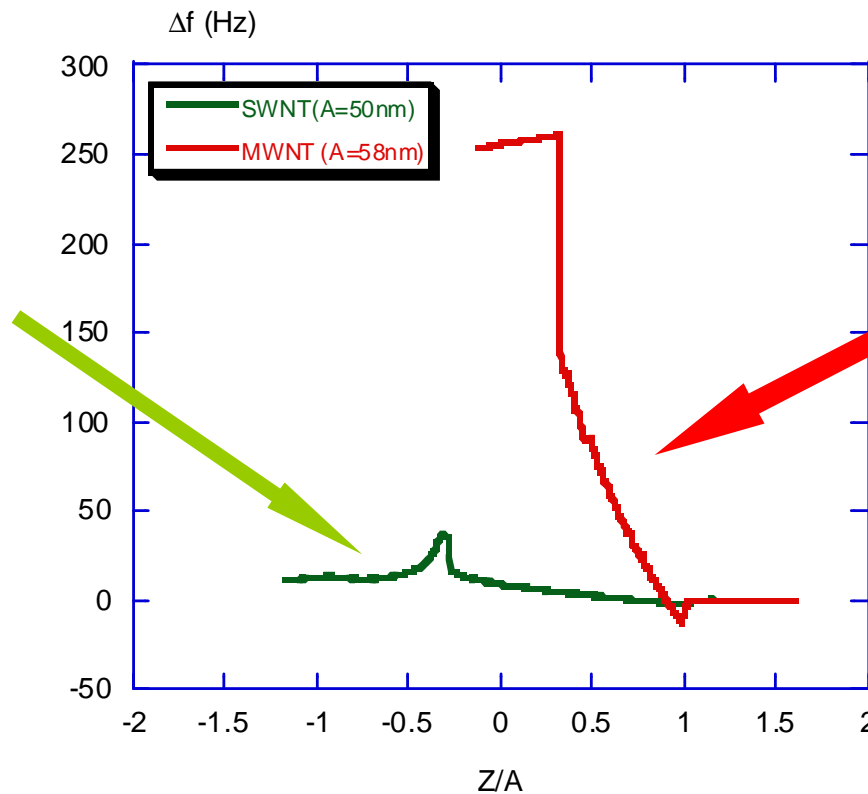
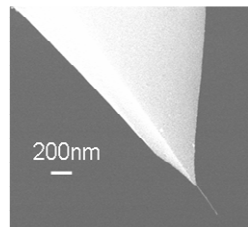
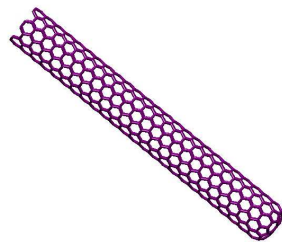
# SWNT vs MWNT

$$\frac{\Delta\nu}{\nu_0} \approx \frac{k_{NT}}{k_{cantilever}}$$

$\Delta\nu$

MWNT : typ. 200 Hz

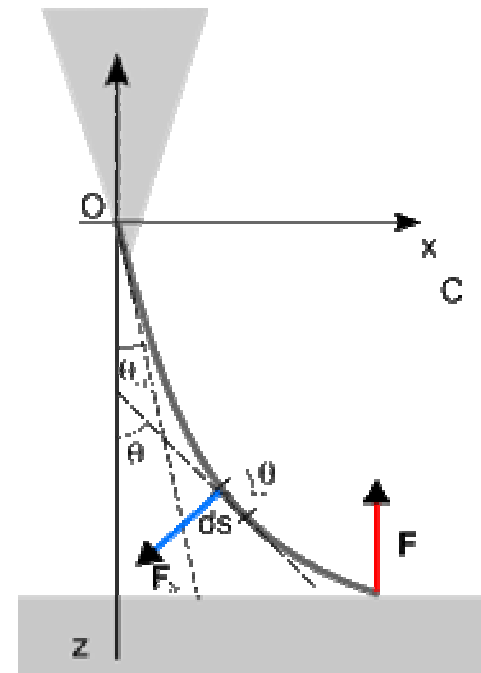
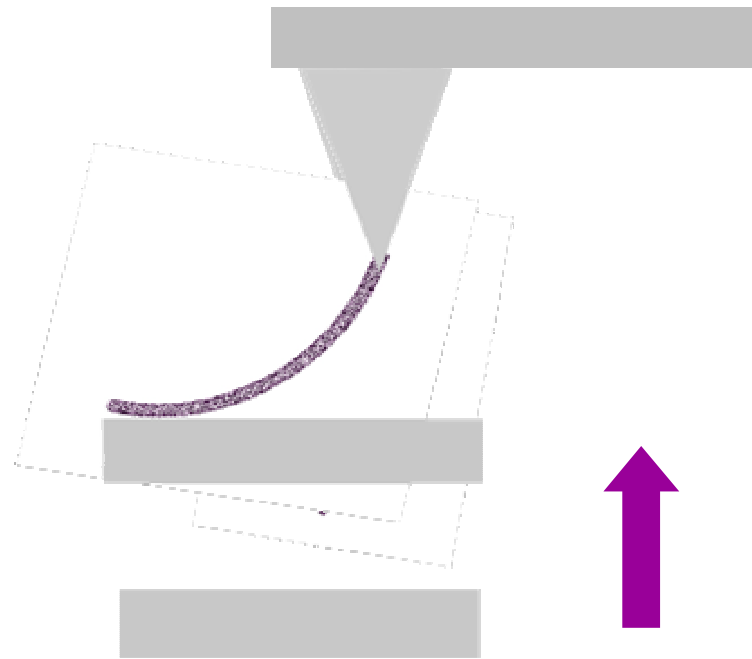
SWNT : typ. 10 Hz



D. Dietzel, et al *Physical Review B* 72, 035445 (2005). YES FROM US 16-18 november 2009

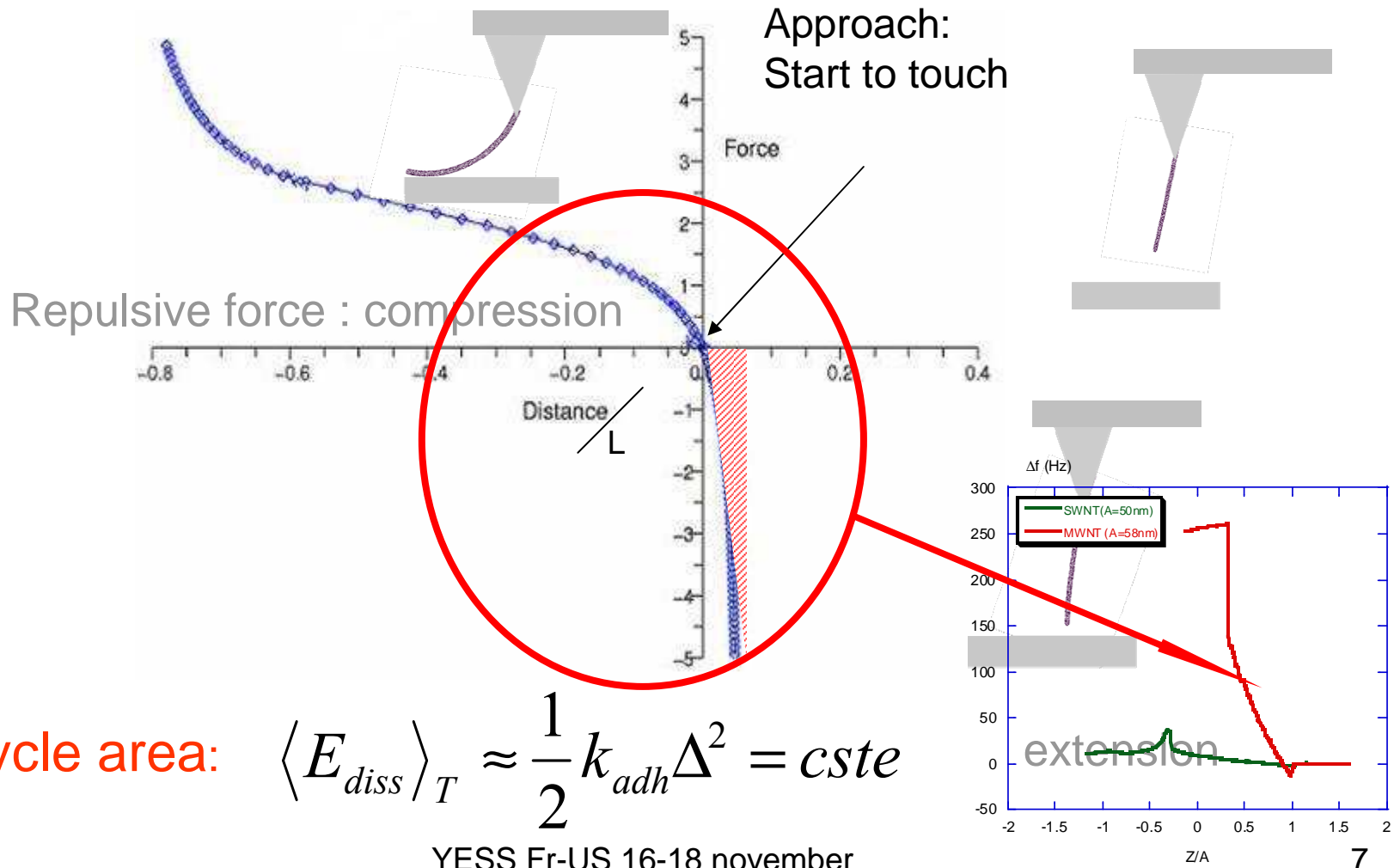
C. Bernard et al *Nanotechnology* 19, 35709-35718 (2008). S. Marsaudon et al, "Applied Scanning Probe". (Springer-2008).

▶ CNT AFM nanoprobe: a simple mechanical system?



# AFM Dynamical mode: Nanotube mechanical cycle

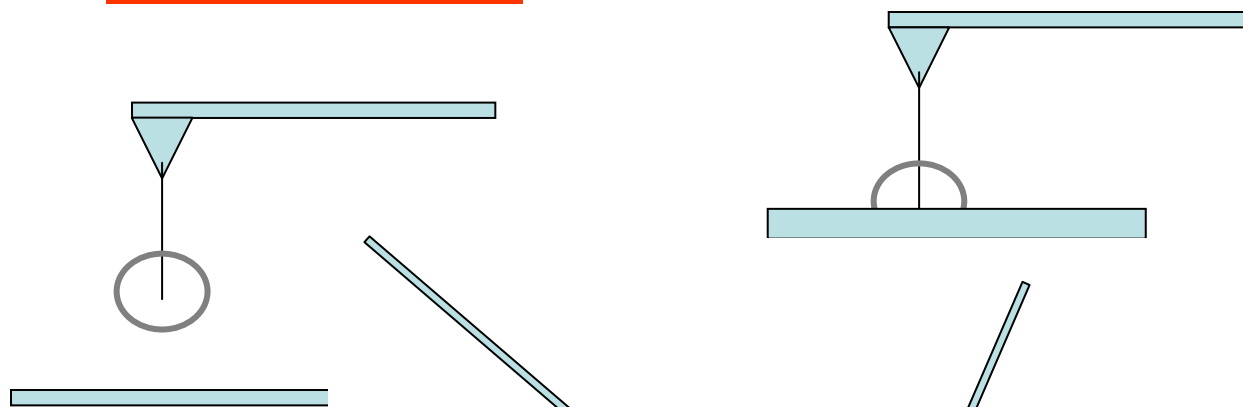
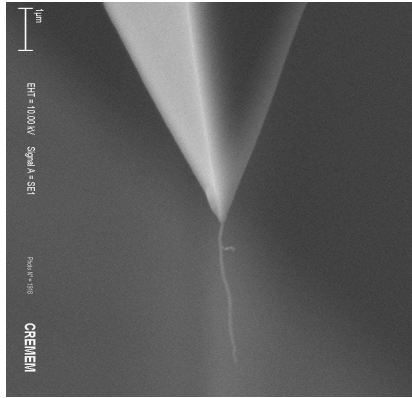
Modl for AFM experiments



Cycle area:  $\langle E_{diss} \rangle_T \approx \frac{1}{2} k_{adh} \Delta^2 = cste$

YESS Fr-US 16-18 november  
2009

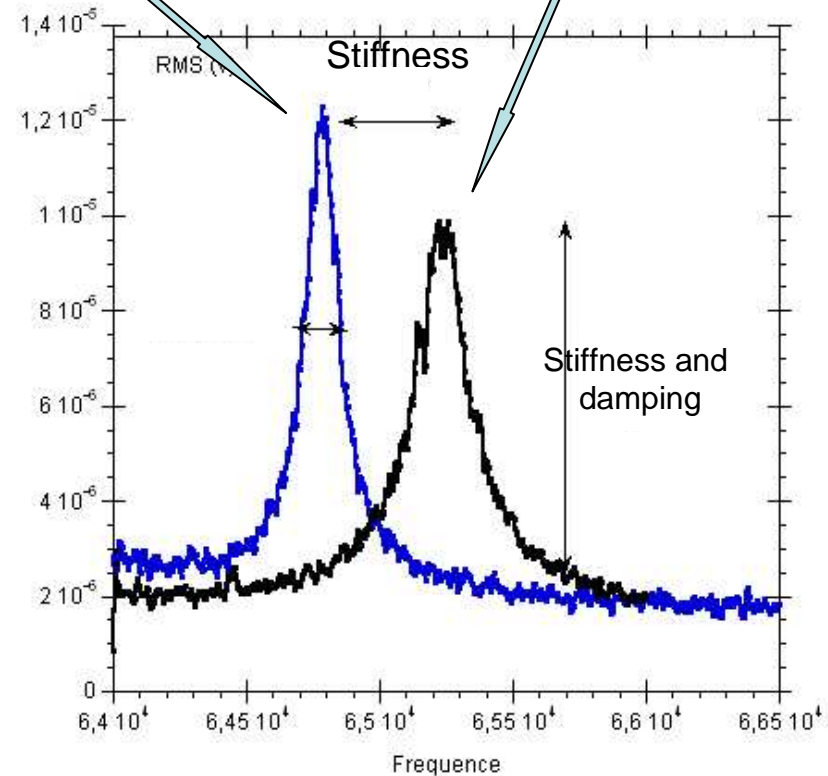
# Thermal Noise



$$\langle X_{\omega}^2 \rangle = \frac{4k_B T \gamma_0}{m^2 [\omega^2 - \omega_0^2]^2 + \gamma_0^2 \omega^2}$$

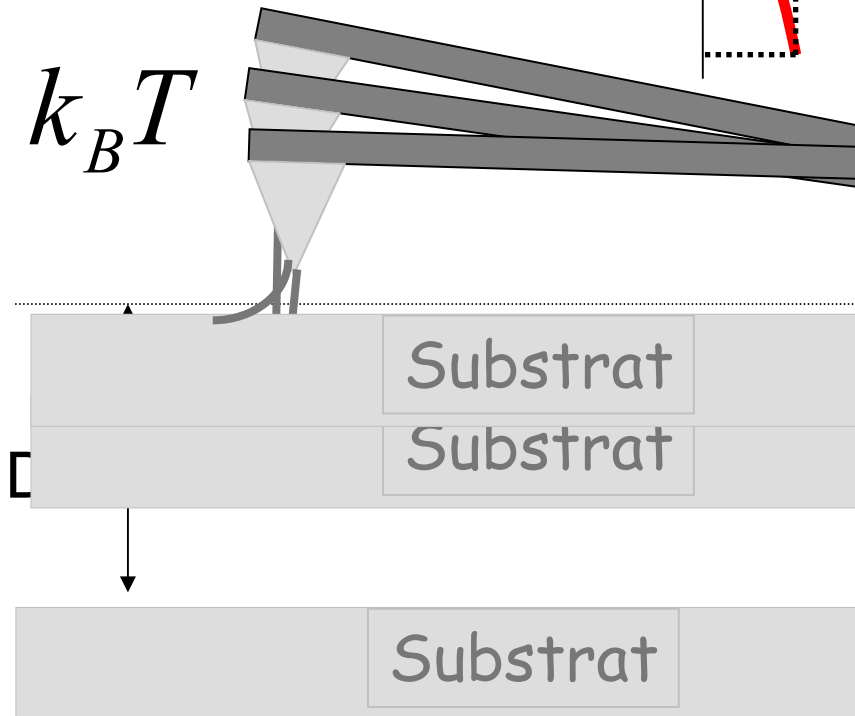
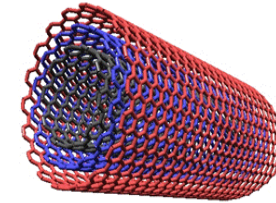
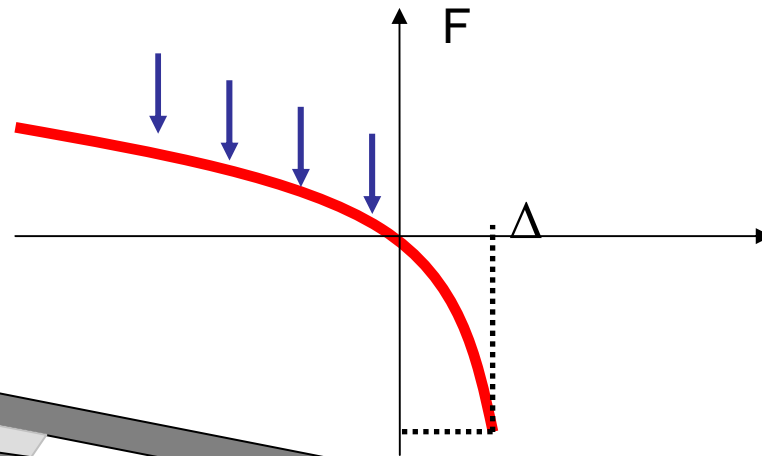
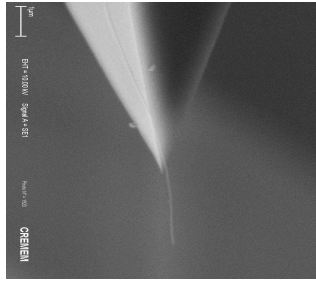
$$\gamma_0 \simeq \rho \frac{\pi}{4} W^2 L \omega \left[ 3.8 \frac{\delta}{W} + 2.7 \left[ \frac{\delta}{W} \right]^2 \right]$$

Moderate vacuum P=5-10 mbar

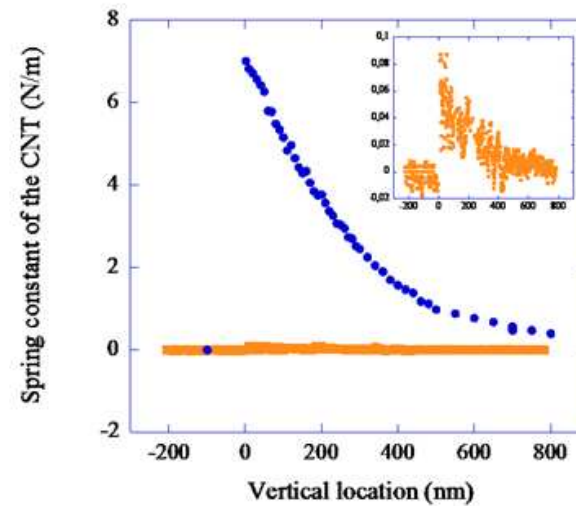
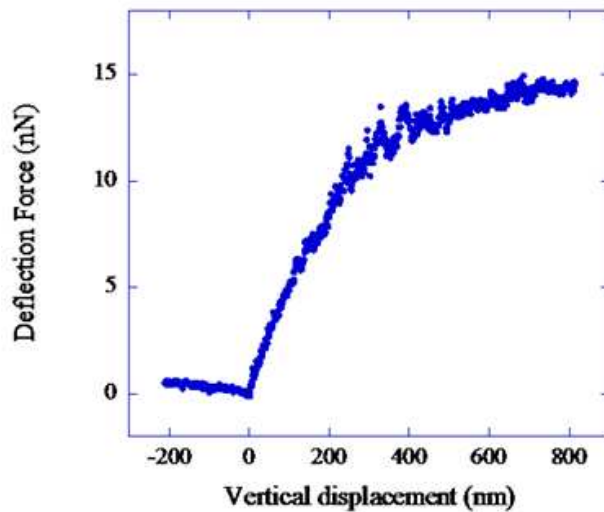
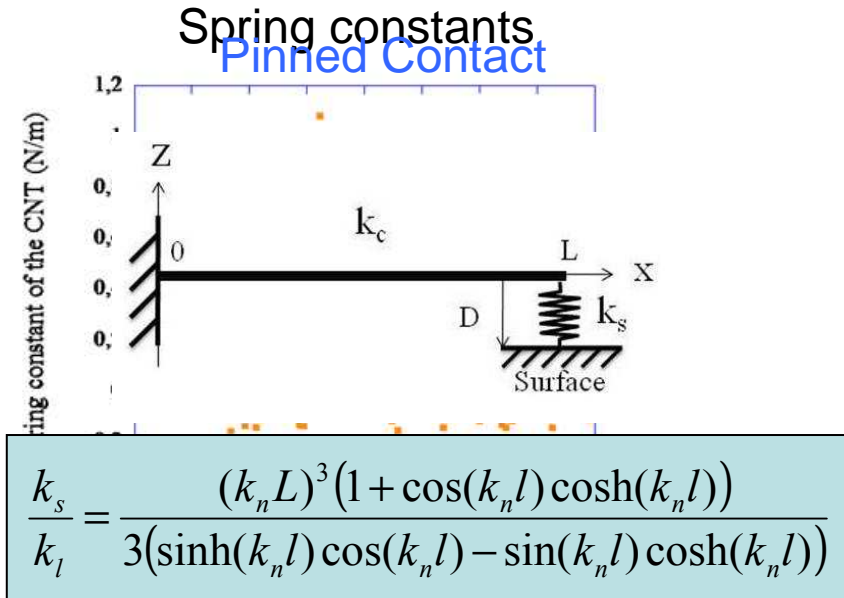
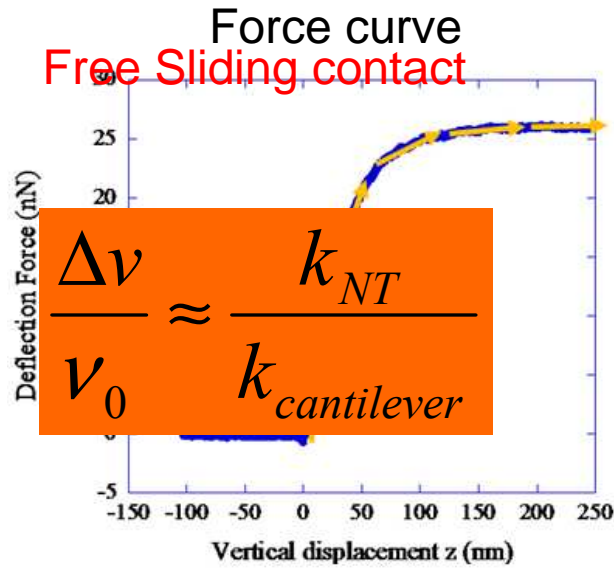


YESS F

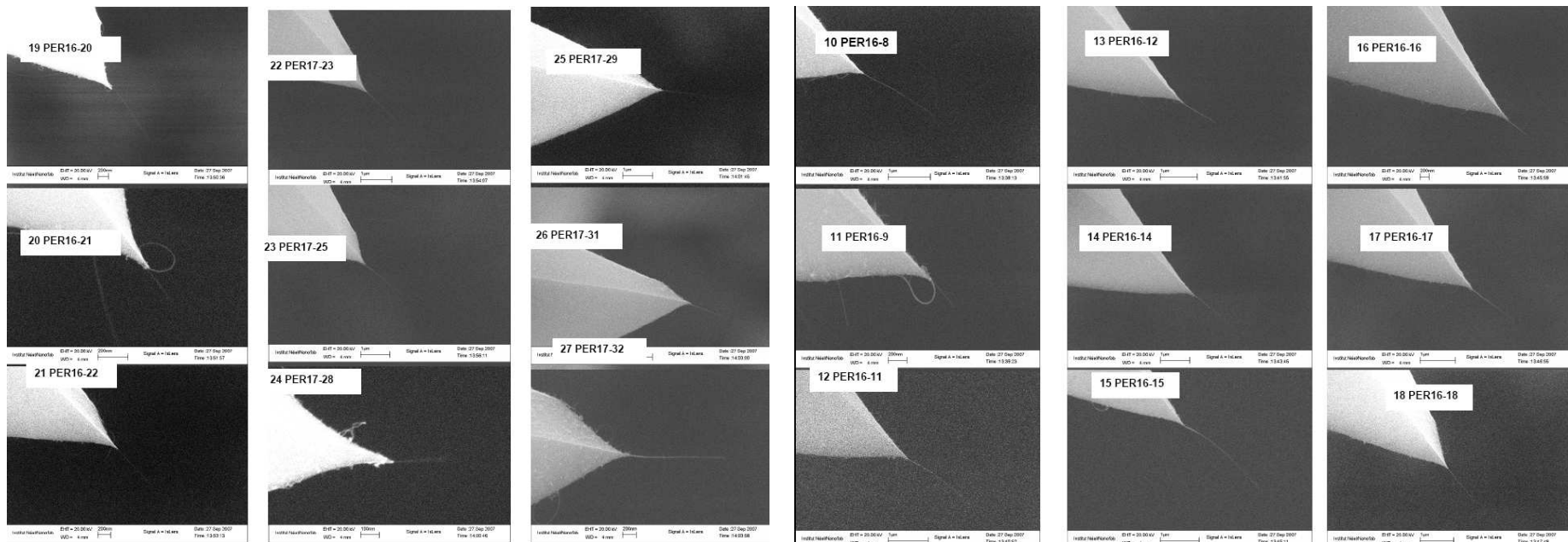
# MWNT Thermal Noise Forcing



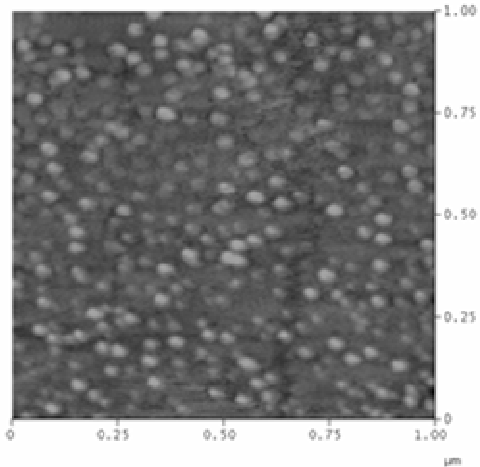
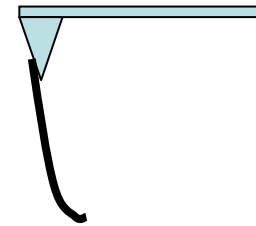
# Free sliding versus pinned CNT contact



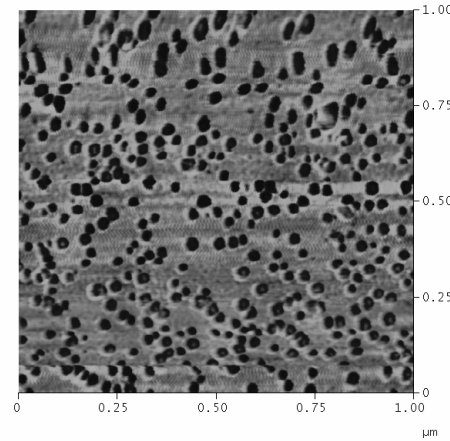
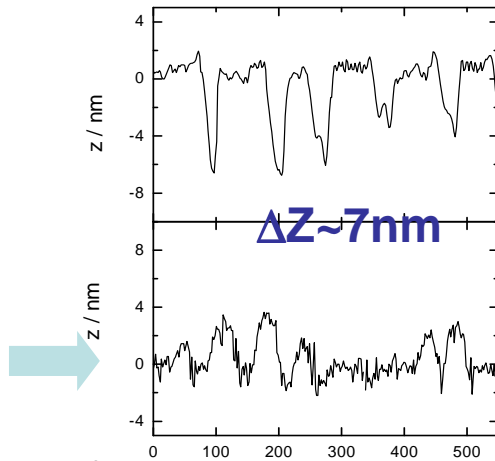
**SWNT**  
**Anne-Marie Bonnot (retired)**  
**Institut Louis Néel Grenoble**  
**(SWNT reactor now in CBMN Bordeaux I)**



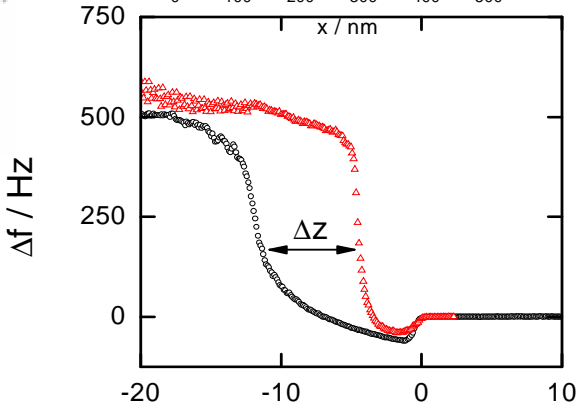
Softer: More rich behaviour, Contact Fluctuations happen



InAs Islands on GaAs



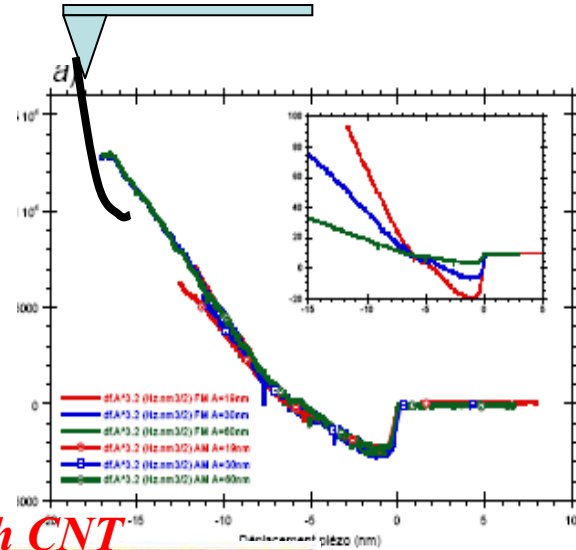
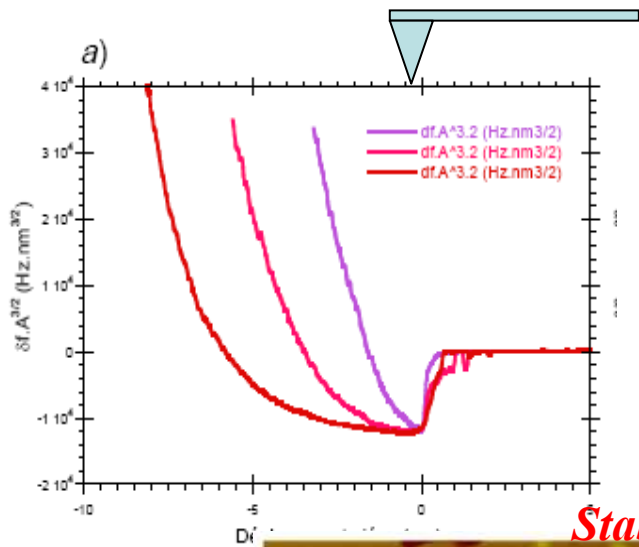
Islands become holes !



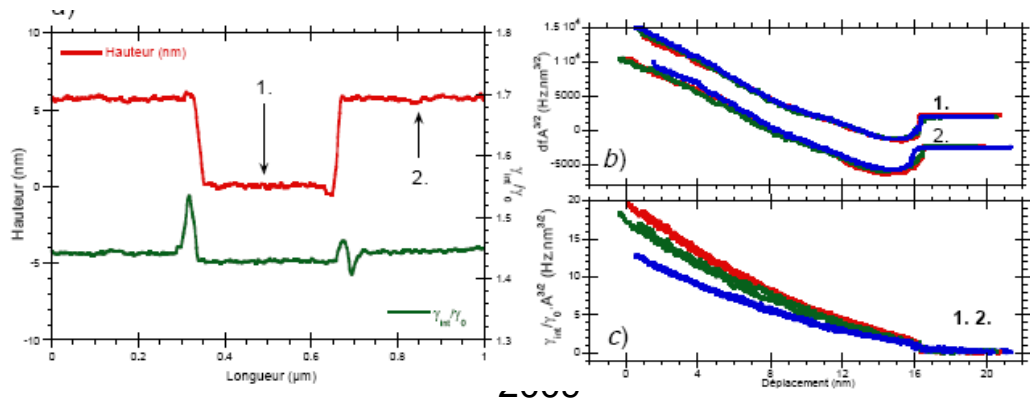
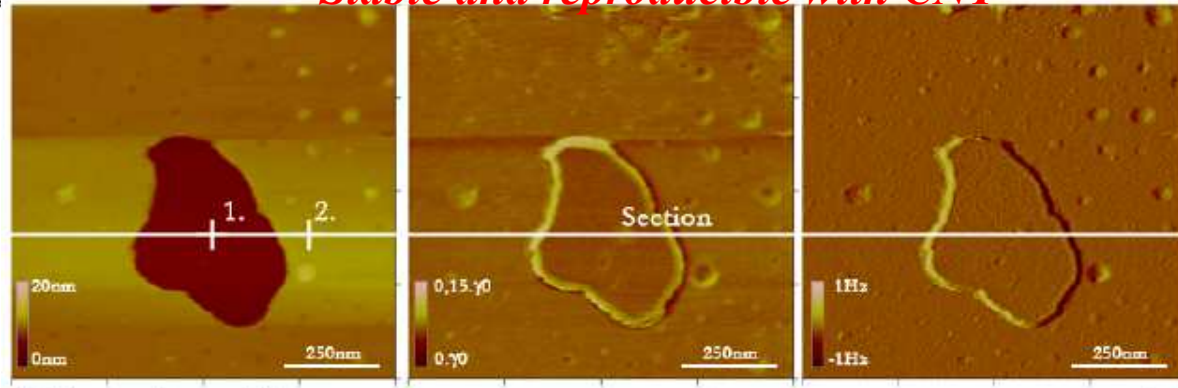
# Phospholipids



# FM-Force Curves

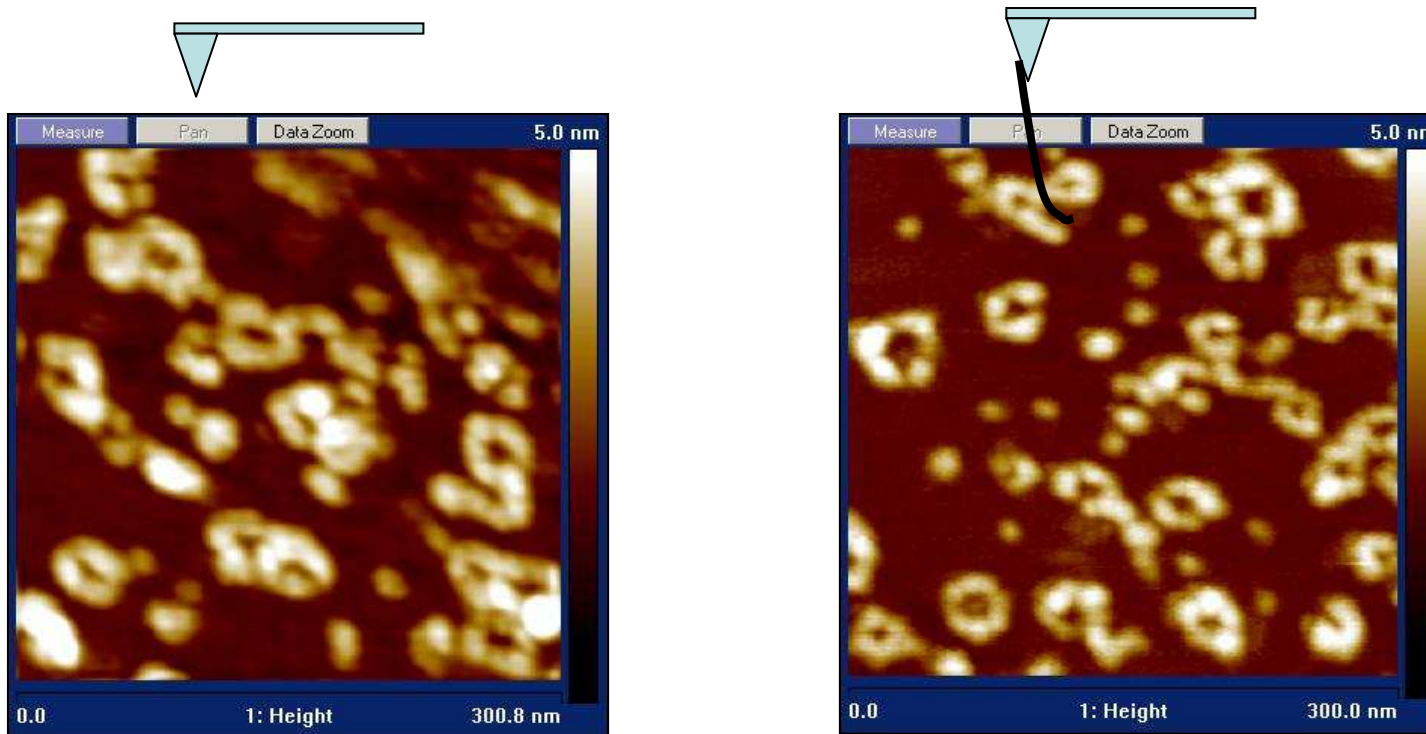


Stable and reproducible with CNT



High resolution **AFM** imaging antibody  
CEA Marcoule  
DSV/iBEB/SBTN/LIRM  
Michael Odorico ; Pierre Parot ; Jean-Luc Pellequer

Ultra sharp tip



Much better: resolution, tip stability...

***Prospects***  
***CNT a versatile AFM Tip***

***Electrochemical nanoreactor with position control  
at the nm scale.***

***Goal: enzymatic activity***

***C. Demaille Univ. Paris Diderot (Head of the project)***  
***T. Michon INRA Villenave d'Ornon.***

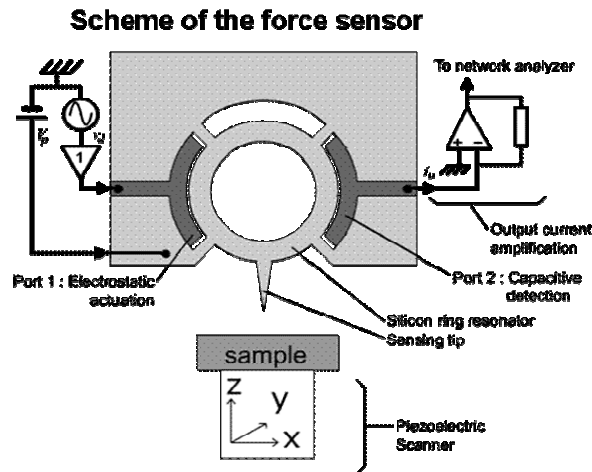
***ANR PIRIBIO***

# Prospects

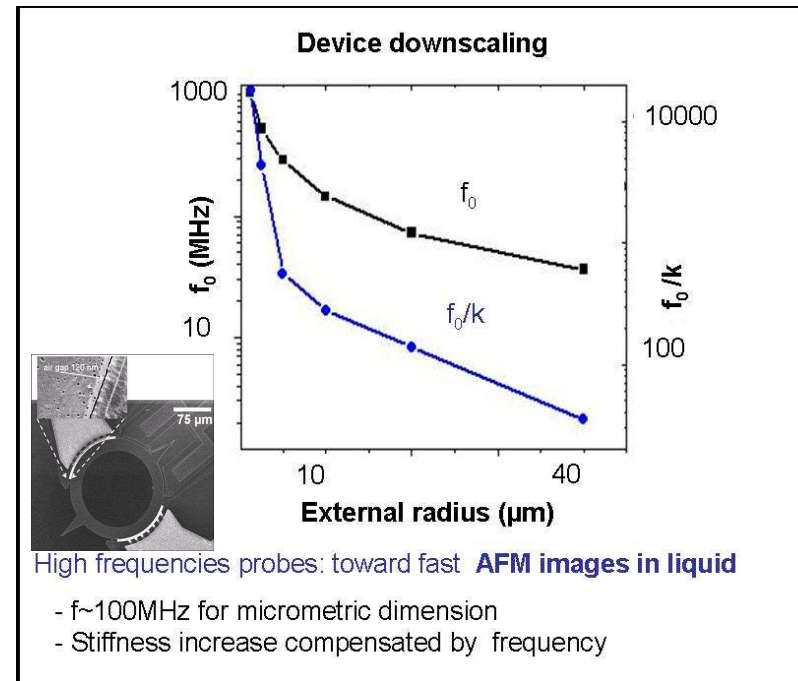
## CNT a versatile AFM Tip

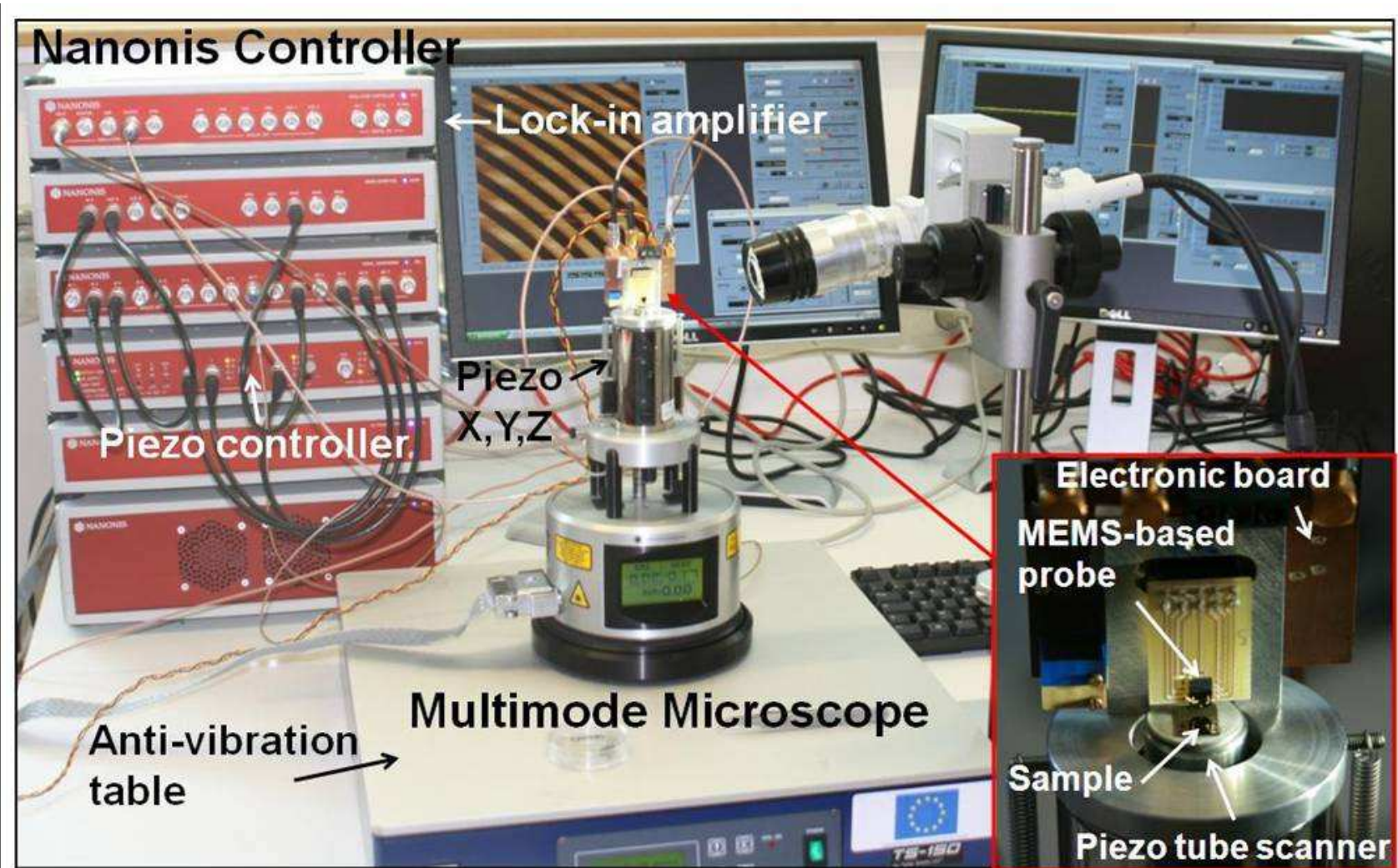
### High speed AFM

B. Legrand, M. Faucher, L. Buchailot IEMN Lille,  
ANR Improve LM



The resonator holds the active oscillating tip.  
The whole NEMS with its electrical connection  
is set at the free end of the cantilever.





# Nanoprobe CNT-Mechanical Properties

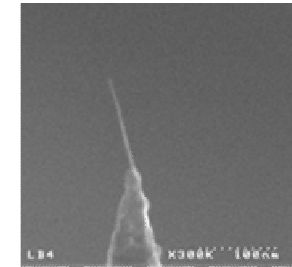
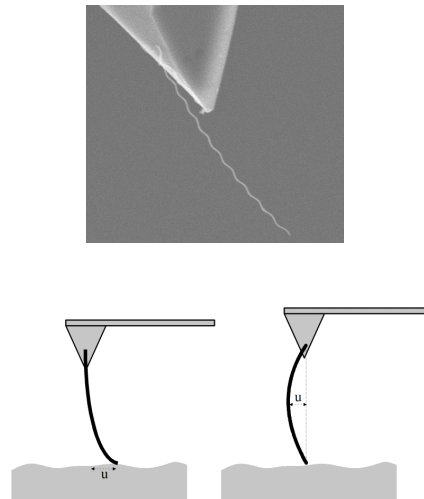
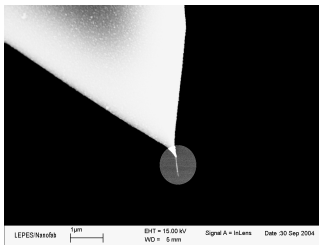
Sophie Marsaudon, Julien Buchoux,

M. Seydou, R. Boisgard, J.P. Aimé,, *Université Bordeaux I.*

Anne-Marie Bonnot, *Institut Néel, Grenoble. Cattien N'Guyen NASA Ames*

Denis Mariolle, Amal Chabli, *CEA-LETI, MINATEC, Grenoble*

L. Buchaillet, M. Faucher, B. Legrand (*IEMN-Villeneuve D'Ascq-(ACI 2005-ANR 2008)*)



D. Dietzel, et al *Physical Review B* 72, 035445 (2005), *Nanotechnology* (2005) 16, p.S73-S78, *JSPM* (2006), C. Bernard et al *Nanoscale Res. Let.* (2007) 309-318 *Nanotechnology*19, 35709-35718 (2008) J. Buchoux et al (2009), M. Seydou et al *Physical Review B* (2009).  
S. Marsaudon et al , “*Applied Scanning Probe Methods*”. (Springer-2009).